

# Janusz Kaczmarek

## List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/7904626/publications.pdf>

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citing authors

#	ARTICLE	IF	CITATIONS
1	A Comprehensive Analysis of Error Sources in Electronic Fully Digital Impedance Bridges. IEEE Transactions on Instrumentation and Measurement, 2021, 70, 1-14.	4.7	12
2	Error sources in electronic fully-digital impedance bridges. , 2020, , .		2
3	Characterization of PXI-Based Generators for Impedance Measurement Setups. IEEE Transactions on Instrumentation and Measurement, 2019, 68, 1806-1813.	4.7	6
4	Errors of Multiplying D/A Converters Used for Precise AC Voltage Division. IEEE Transactions on Instrumentation and Measurement, 2019, 68, 1821-1826.	4.7	1
5	Practical Precision Electrical Impedance Measurement for the 21 <sup>st</sup> Century â€“ EMPIR Project 17RPT04 VersiCal. , 2019, , .		2
6	Errors of Multiplying D/A Converters Used for Precise AC Voltage Division. , 2018, , .		1
7	Characterization of PXI-Based Generators for Impedance Measurement Setups. , 2018, , .		1
8	A PXI-Based Calibration System for Low-Value AC Resistors. IEEE Transactions on Instrumentation and Measurement, 2018, 67, 905-911.	4.7	12
9	Impedance Comparison Using Unbalanced Bridge With Digital Sine Wave Voltage Sources. IEEE Transactions on Instrumentation and Measurement, 2015, 64, 3380-3386.	4.7	16
10	A High-Resolution PXI Digitizer for a Low-Value-Resistor Calibration System. IEEE Transactions on Instrumentation and Measurement, 2013, 62, 1783-1788.	4.7	19
11	Integrated System for Monitoring and Control of the National Time and Frequency Standard. IEEE Transactions on Instrumentation and Measurement, 2013, 62, 2828-2838.	4.7	13
12	Characterization of a digitizer for a low value resistor calibration system in the audio-frequency band. , 2012, , .		3
13	Impedance Measurement With the D-Optimum Experimental Conditions. IEEE Transactions on Instrumentation and Measurement, 2009, 58, 2535-2543.	4.7	7